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TITLE

A sequential test and a sequential sampling plan based on the process capability index C_{pmk}

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Abstract

In this study we propose a sequential test for hypothesis testing on the C_{pmk} process capability index.

Furthermore, we propose a sequential sampling plan for lot acceptance based on C_{pmk} . We compare the statistical properties of the sequential procedures with the performance of the corresponding non-sequential methodologies by carrying out an extensive simulation study. The results show that the proposed sequential methods make it possible to reach decisions much more quickly, on average, than the fixed sample size procedures with the same discriminating power.

Keywords: process capability indices; acceptance sampling plan; average sample size, power function, producer and consumer risks

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1. Introduction

Process capability indices are the tools usually used for assessing processes performance in relationship to the design specifications. If we represent the process mean with μ , the process standard deviation with σ , the specification limits with LSL and USL , the half-length of the specification interval as $d = (USL - LSL)/2$, the midpoint of the specification interval as $m = (USL + LSL)/2$, and the target value of the process as T , the capability indices most widely used are (Kotz and Lovelace 1998, Polansky and Kirmani 2003, Pearn and Kotz 2006, Montgomery 2009): the potential capability index

$$C_p = \frac{USL - LSL}{6\sigma} = \frac{d}{3\sigma}, \quad (1)$$

the actual capability index

$$C_{pk} = \frac{d - |\mu - \frac{1}{2}(USL + LSL)|}{3\sigma} = \frac{d - |\mu - m|}{3\sigma}, \quad (2)$$

the loss-based capability index

$$C_{pm} = \frac{USL - LSL}{6\sqrt{\sigma^2 + (\mu - T)^2}} = \frac{d}{3\sqrt{\sigma^2 + (\mu - T)^2}} \quad (3)$$

and the index

$$C_{pmk} = \frac{d - |\mu - m|}{3\sqrt{\sigma^2 + (\mu - T)^2}}, \quad (4)$$

which is constructed by combining the indices C_{pk} and C_{pm} . Note that, for processes with target value set to the mid-point of the specification limits ($T=m$), the index C_{pmk} can be rewritten as

$$C_{pmk} = \frac{d/\sigma - |\xi|}{3\sqrt{1 + \xi^2}}, \quad (5)$$

where $\xi = \frac{\mu - T}{\sigma}$.

In the context of contractual agreements, it is often a requirement to provide evidence that a manufacturing process satisfies a minimum level of capability. The decision-making problem of

demonstrating whether the process capability exceeds a predetermined capability requirement can be approached in terms of hypothesis testing.

Literature concerning process capability hypothesis testing includes significant amounts of interesting research. To name but a few: the pioneering work by Kane (1986); the tests on C_{pk} investigated by Pearn and Chen (1999), Perakis and Xekalaki (2003), Pearn and Lin (2004), Chen and Hsu (2004) and Lin (2006); the Bayesian approach proposed by Fan and Kao (2006); the hypothesis testing studies on C_{pmk} by Pearn and Lin (2002) and Pearn et al. (2005); the model free approach testing procedure proposed by Vännman and Kulachi (2002); the study of the effect of pooled and un-pooled variance estimators on hypothesis testing concerning C_{pm} by Hubele and Vännman (2004); the unified analysis of hypothesis testing with process capability indices by Lepore and Palumbo (2015); the sequential procedure for testing the equality of two indices C_{pm} by Hussein et al. (2012), and the sequential test proposed by Scagliarini (2018).

Furthermore, due to their ability to summarize adherence to design specifications in a single number, capability indices have also proven to be useful in the framework of lot-by-lot acceptance-sampling plans.

Sampling plans provide the producer and consumer with general decision rules for product acceptance while meeting their needs for product quality and managing the risks of not adequately reflecting the quality conditions of the lot. Acceptance sampling plans basically consist of a required sample size for inspection and an acceptance criterion, so that the producer and consumer risks meet predetermined standards.

Sampling plans can be classified by: variables when the quality characteristics are measured on a numerical or continuous scale; attributes when characteristics are expressed on a “go, no-go” basis. Generally, numerical measurements of quality characteristics provide more information about the manufacturing process or lot than do attributes data. Thus, in today’s manufacturing industries where the allowable proportion of nonconforming products is very low, often measured in parts per million (PPM), variables sampling plans become very attractive since they allow the sample size to be significantly reduced.

The relevance of process capability indices in the context of acceptance variables sampling plans is confirmed by numerous studies, including: Arizono et al. (1997); Pearn and Wu (2006a, and 2006b); Wu and Pearn (2008); Yen and Chang (2009); Negrin et al. (2009 and 2011); Wu et al. (2012); Lepore et al. (2018).

In this study, we propose a sequential test for the index C_{pmk} and a sequential sampling plan for lot acceptance based on C_{pmk} .

We analytically derive the test statistic of the sequential test and describe in detail the testing procedure.

We then compare the statistical properties of the sequential test with those of the most widely used non-sequential test by performing an extensive simulation study.

In analysing the performance of the sequential procedure, several issues should be taken into consideration, such as, for example, the behaviour of the stopping sample size required by the test to decide in favour of H_0 and H_1 . This type of analysis is quite complex. However, it is more intuitive and easier to develop if worked out in the framework of a variables sampling plan based on C_{pmk} . In such a way we can also propose a sequential sampling plan for variables which uses the index C_{pmk} as the benchmark for acceptance of a batch of products.

The results show that the proposed sequential procedures make it possible to reach decisions which, on average, allow the sample size to be reduced when compared with the non-sequential procedures, with consequent financial benefits and without any loss in quality.

The paper is organized as follows. In Section 2, we review the non-sequential test, proposed by Pearn and Lin (2002), used for assessing whether a process is capable or not based on the C_{pmk} process capability index. In Section 3, we present the general sequential test procedure, proposed by Hussein (2005) and Hussein et al. (2012). In Section 4, we analytically obtain the test statistic and propose the sequential procedure for hypotheses testing on C_{pmk} . In Section 5, using the results obtained in Section 4, we develop a sequential sampling plan based on C_{pmk} . In Section 6, we study the performance of the sequential test and the sequential sampling plan through a set of Monte Carlo simulations, and compare the proposed methods with the corresponding non-sequential procedures. Section 7 contains a discussion of the results. Finally, our concluding remarks are given in Section 8.

2. Hypothesis test for the index C_{pmk}

To verify whether a process conforms to specifications using the index C_{pmk} the hypotheses of interest are:

$$H_0 : C_{pmk} \leq C_{pmk0} \text{ (the process is not capable),}$$

versus

$$H_1 : C_{pmk} > C_{pmk0} \text{ (the process is capable).}$$

Assuming a normally distributed quality characteristic, $X \sim N(\mu, \sigma^2)$, Pearn and Lin (2002) proposed a statistical test (PL-test) based on the distribution of the estimator:

$$\hat{C}_{pmk} = \min \left\{ \frac{USL - \bar{X}}{3\sqrt{S_n^2 + (\bar{X} - T)^2}}, \frac{\bar{X} - LSL}{3\sqrt{S_n^2 + (\bar{X} - T)^2}} \right\} = \frac{d - |\bar{X} - T|}{3\sqrt{S_n^2 + (\bar{X} - T)^2}}, \quad (6)$$

where $\bar{X} = \sum_{i=1}^n X_i / n$ and $S_n^2 = \sqrt{\sum_{i=1}^n (X_i - \bar{X})^2} / n$ are the maximum likelihood estimators of μ and σ^2 , respectively.

For the case $T = (USL + LSL)/2$, the cumulative distribution function of \hat{C}_{pmk} can be expressed as

$$F_{\hat{C}_{pmk}}(x) = 1 - \int_0^{b\sqrt{n}/(1+3x)} G\left(\frac{(b\sqrt{n}-t)^2}{9x^2} - t^2\right) \left[\phi(t + \xi\sqrt{n}) + \phi(t - \xi\sqrt{n}) \right] dt \quad (7)$$

for $x > 0$, where $b = d/\sigma$, $G(\cdot)$ is the cumulative distribution function of the chi-square distribution χ_{n-1}^2 , and $\phi(\cdot)$ is the probability density function of the standard normal distribution.

The decision rule of the test is to find C_0 and reject $H_0 : C_{pmk} \leq C_{pmk0}$ if $\hat{C}_{pmk} > C_0$ and do not reject H_0 otherwise.

Given the values of the type-I error probability α_{PL} , the capability requirement C_{pmk0} , the sample size n and the parameter ξ , the critical value C_0 can be obtained by solving the equation

$$\int_0^{b\sqrt{n}/(1+3C_0)} G\left(\frac{(b\sqrt{n}-t)^2}{9C_0^2} - t^2\right) \left[\phi(t + \xi\sqrt{n}) + \phi(t - \xi\sqrt{n}) \right] dt = \alpha_{PL}. \quad (8)$$

It can be noted that equation (8) depends on the additional parameter ξ , which in real applications is unknown. The estimation of ξ introduces additional sampling errors in finding the critical value C_0 .

Therefore, to eliminate the need to estimate ξ , Pearn and Lin (2002) studied the behaviour of C_0 as a function of ξ . They found that the condition $\xi = 0.5$ should provide conservative critical values (the condition would be $|\xi| = 0.5$, however since (8) is an even function of ξ , the results for positive

and negative values are the same). The results for C_0 and the sample size n , for several combinations of α_{PL} and C_{pmk0} , are given by Pearn and Lin (2002) in their Tables 1-5.

Hence, for $C_{pmk1} \geq C_{pmk0}$, given α_{PL} , n and C_0 , the power of the PL-test can be written as

$$\begin{aligned} \pi_{PL}(C_{pmk1}) &= \Pr(\hat{C}_{pmk} \geq C_0 | C_{pmk} = C_{pmk1}) \\ &= \int_0^{b\sqrt{n}/(1+3C_0)} G\left(\frac{(b\sqrt{n}-t)^2}{9C_0^2} - t^2\right) \left[\phi(t + \xi\sqrt{n}) + \phi(t - \xi\sqrt{n})\right] dt, \end{aligned} \quad (9)$$

where $b = d/\sigma = 3C_{pmk1}\sqrt{1+\xi^2} + |\xi|$.

3. A general sequential method

Here we describe the general sequential testing procedure proposed by Hussein (2005) and Hussein et al. (2012). In Section 4, this general multivariate framework will be specified for sequential hypothesis testing on C_{pmk} .

Let us denote with $\mathbf{X}_1, \mathbf{X}_2, \dots, \mathbf{X}_k, \dots$, a sequence of independent observations of the random vector \mathbf{X} , collected over time, with $\mathbf{X} \in R^d$. We assume that these data come from a common multivariate distribution with density function $f(\mathbf{x}; \boldsymbol{\theta})$, where the $d \times 1$ vector of parameters $\boldsymbol{\theta}$ is unknown.

We are interested in testing

$$H_0 : h(\boldsymbol{\theta}) = \mathbf{0} \text{ versus } H_1 : h(\boldsymbol{\theta}) \neq \mathbf{0}, \quad (10)$$

where $h(\boldsymbol{\theta}) : R^d \rightarrow R^q$, with $q \leq d$, is a function with first order derivative matrix denoted by $H(\boldsymbol{\theta})$.

Let us assume that for $\boldsymbol{\theta} \in \Theta \subset R^d$ with $q \leq d$ the following regularity conditions hold (Hussein et al. 2012, Scholz 2006):

C1. The distribution function $F(\mathbf{x}; \boldsymbol{\theta})$ of the random vector \mathbf{X} is identifiable over $\boldsymbol{\theta} \in \Theta$, i.e. if $\boldsymbol{\theta} \neq \boldsymbol{\theta}'$, then $F(\mathbf{x}; \boldsymbol{\theta})$ and $F(\mathbf{x}; \boldsymbol{\theta}')$ are different distributions.

C2. There exists an open subset, $\Theta_0 \subset \Theta$, containing the true value of the parameter under H_0 , such that the partial derivatives

$$\frac{\partial}{\partial \theta_i} \ln f(\mathbf{x}; \boldsymbol{\theta}), \frac{\partial^2}{\partial \theta_i \partial \theta_j} \ln f(\mathbf{x}; \boldsymbol{\theta}), \frac{\partial^3}{\partial \theta_i \partial \theta_j \partial \theta_k} \ln f(\mathbf{x}; \boldsymbol{\theta})$$

exist, are exchangeable, and are continuous for all $\mathbf{x} \in R^l$, $\boldsymbol{\theta} \in \Theta_0$.

C3. For each $\boldsymbol{\theta} \in \Theta_0$ and $k = 1, 2, 3, \dots$, the score equation $\sum_{i=1}^k \frac{\partial \ln f(\mathbf{x}; \boldsymbol{\theta})}{\partial \boldsymbol{\theta}} = 0$ has a unique solution.

C4. There are functions of \mathbf{x} , $M_1(\mathbf{x})$ and $M_2(\mathbf{x})$, that have finite expectations under any of the parameter values, $\boldsymbol{\theta} \in \Theta_0$, such that

$$\left| \frac{\partial}{\partial \theta_i} \ln f(\mathbf{x}; \boldsymbol{\theta}) \right| \leq M_1(\mathbf{x}), \left| \frac{\partial^2}{\partial \theta_i \partial \theta_j} \ln f(\mathbf{x}; \boldsymbol{\theta}) \right| \leq M_2(\mathbf{x}), \left| \frac{\partial^3}{\partial \theta_i \partial \theta_j \partial \theta_k} \ln f(\mathbf{x}; \boldsymbol{\theta}) \right| \leq M_2(\mathbf{x}),$$

for all $\boldsymbol{\theta} \in \Theta_0$, $1 \leq i, j, k \leq d$.

C5. $E_{\boldsymbol{\theta}}(\partial / \partial \theta_i) \ln f(\mathbf{x}; \boldsymbol{\theta}) = 0$, $1 \leq i \leq d$, $\boldsymbol{\theta} \in \Theta_0$, where $E_{\boldsymbol{\theta}}(\cdot)$ denotes that the expectation is parameterized by $\boldsymbol{\theta}$.

C6. The inverse of the Fisher information matrix $I^{-1}(\boldsymbol{\theta})$ and its elements

$I_{ij}(\boldsymbol{\theta}) = E_{\boldsymbol{\theta}} \left[\left(\partial^2 / \partial \theta_i \partial \theta_j \right) \ln f(\mathbf{x}; \boldsymbol{\theta}) \right]$ exist and are continuous for all $\boldsymbol{\theta} \in \Theta_0$, $1 \leq i, j \leq d$.

C7. $\text{Var}_{\boldsymbol{\theta}} \left[\left(\partial^2 / \partial \theta_i \partial \theta_j \right) \ln f(\mathbf{x}; \boldsymbol{\theta}) \right] < \infty$ for $1 \leq i, j \leq d$.

Let us further assume that:

C8. $E_{\boldsymbol{\theta}} \left| \left(\partial / \partial \theta_i \right) \ln f(\mathbf{x}; \boldsymbol{\theta}) \right|^{2+\delta} < \infty$, $i = 1, 2, \dots, d$, and for some $\delta > 0$.

C9. The function $h(\boldsymbol{\theta})$ is continuously differentiable over Θ_0 , and its first-order derivative matrix $H(\boldsymbol{\theta})$ is bounded and of rank q .

Let us now consider a fixed sample design with sample size equal to k and let us consider the Wald's statistic

$$W_k = kh(\hat{\boldsymbol{\theta}}_k) \left[H^t(\boldsymbol{\theta}) I^{-1}(\boldsymbol{\theta}) H(\boldsymbol{\theta}) \right]^{-1} h(\hat{\boldsymbol{\theta}}_k)^t, \quad (11)$$

where $\hat{\boldsymbol{\theta}}_k$ is a consistent estimator of $\boldsymbol{\theta}$.

Hussein et al. (2012) in Theorem 1 showed that under H_0 , and if conditions C1-C9 hold, there exists

an independent Wiener process, $B_j(t)$, $j = 1, 2, \dots, q$, such that for $\alpha \leq \frac{1}{2} - 1/(2 + \delta)$ with $\delta > 0$,

$$\sup_{1 \leq t < \infty} |W_{[kt]} - U_{[kt]}| = O(k^{-\alpha} (\ln \ln k)^{1/2}), \quad (12)$$

where, $O(\cdot)$ means "of the same order as",

$$U(x) = \frac{1}{x} \sum_{j=1}^q B_j^2(x), \quad (13)$$

$$W_{[kt]} = [kt] h(\hat{\boldsymbol{\theta}}_{[kt]}) [H'(\boldsymbol{\theta}) I^{-1}(\boldsymbol{\theta}) H(\boldsymbol{\theta})]^{-1} h(\hat{\boldsymbol{\theta}}_{[kt]})^t \quad (14)$$

and $[\cdot]$ denotes the integer part of its argument.

The statistic W_k can therefore be approximated by a functional of Brownian motions.

Furthermore, the authors derived the limiting distribution of W_k . In detail they showed that (Corollary 1):

- Under the conditions of Theorem 1

$$\max_{1 \leq k \leq n} \left[\frac{k}{n} W_k \right]^{1/2} \xrightarrow{D} \sup \left(\sum_{j=1}^q B_j^2(t) \right)^{1/2}, \quad (15)$$

where \xrightarrow{D} denotes convergence in distribution;

- When replacing the unknown $\boldsymbol{\theta}$ in the term $H'(\boldsymbol{\theta}) I^{-1}(\boldsymbol{\theta}) H(\boldsymbol{\theta})$ with any almost surely convergent estimator, Corollary 1 remains valid.

Therefore, Hussein et al. (2012) defined the following as test statistic

$$W_k^* = k h(\hat{\boldsymbol{\theta}}_k) [H'(\hat{\boldsymbol{\theta}}_k) I^{-1}(\hat{\boldsymbol{\theta}}_k) H(\hat{\boldsymbol{\theta}}_k)]^{-1} h(\hat{\boldsymbol{\theta}}_k)^t, \quad (16)$$

where $\hat{\boldsymbol{\theta}}_k$ is the maximum likelihood estimator of $\boldsymbol{\theta}$, and proposed the following α_s -level sequential test truncated at the maximum allowable sample size n_0 .

The sequential test procedure is performed as follows:

- For $k = 2, 3, \dots, n_0$ calculate the statistic

$$W_k^{*(1)} = \sqrt{k/n_0} \sqrt{W_k^*}; \quad (17)$$

- Reject the hypothesis H_0 the first time that $W_k^{*(1)}$ exceeds the critical value w_{α_s} . Given the Type I error probability α_s , the critical value w_{α_s} can be obtained in accordance with Borodin and Salminen (1996);
- If $W_k^{*(1)}$ does not exceed w_{α_s} by n_0 , then stop the sampling and do not reject H_0 .

The maximum sample size n_0 can be decided on the basis of financial, ethical or statistical reasons, for example as the smallest one that achieves a desired power level.

4. A sequential test for C_{pmk}

Let us now consider the hypothesis

$$H_0 : C_{pmk} = C_{pmk0}, \quad (18)$$

versus

$$H_1 : C_{pmk} \neq C_{pmk0} \quad (19)$$

and assume that the quality characteristic is normally distributed $X \sim N(\mu, \sigma^2)$.

For $C_{pmk} \geq 0$, H_0 is equivalent to

$$H_0 : \ln\left((C_{pmk})^2\right) - \ln\left((C_{pmk0})^2\right) = 0 \quad (20)$$

and the alternative hypothesis is equivalent to

$$H_1 : \ln\left((C_{pmk})^2\right) - \ln\left((C_{pmk0})^2\right) \neq 0. \quad (21)$$

Let us define the function $h(\boldsymbol{\theta})$ as

$$h(\boldsymbol{\theta}) = \ln\left((C_{pmk})^2\right) - \ln\left((C_{pmk0})^2\right) = \ln\left[\left(d/\sigma - |\xi|\right)^2 / 9(1 + \xi^2) C_{pmk0}^2\right], \quad (22)$$

where, in analogy with the PL-test, we assume ξ as known. In such a way, as far as this issue is concerned, the sequential test is comparable with the PL-test. Please note that this assumption will be relaxed later in this Section and the effects ξ on the sequential test will be analysed in Section 7.

With ξ assumed to be known, we have $\boldsymbol{\theta} = \sigma^2$ and $h(\boldsymbol{\theta}) : R^d \rightarrow R^q$ with $d=q=1$ (Appendix A provides details concerning the satisfaction of conditions C1 to C9). Thus, the first order derivative matrix $H(\boldsymbol{\theta})$ can be written as

$$H(\boldsymbol{\theta}) = \left[\frac{\partial h(\sigma^2)}{\partial \sigma^2} \right] = \frac{d \left[\sqrt{\sigma^2} |\xi| - d \right]}{\sigma^2 \left(\xi^2 \sigma^2 - 2d |\xi| \sqrt{\sigma^2} + d^2 \right)}. \quad (23)$$

In the case at hand the statistic W_k^* is

$$W_k^* = kh^2(\hat{\boldsymbol{\theta}}_k) \left[H'(\hat{\boldsymbol{\theta}}_k) I^{-1}(\hat{\boldsymbol{\theta}}_k) H(\hat{\boldsymbol{\theta}}_k) \right]^{-1}, \quad (24)$$

where $\hat{\boldsymbol{\theta}}_k = S_k^2$ with $S_k^2 = \sum_{i=1}^k (X_i - \bar{X}_k)^2 / k$, the function $h(\hat{\boldsymbol{\theta}}_k)$ is given by

$$h(\hat{\theta}_k) = \ln \left[\left(d/\sqrt{S_k^2} - |\xi| \right)^2 / 9(1 + \xi^2) C_{pmk0}^2 \right] \quad (25)$$

and the partial derivative matrix of $h(\theta)$ computed at $\hat{\theta}_k$ can be written as

$$H(\hat{\theta}_k) = \frac{d \left[\sqrt{S_k^2} |\xi| - d \right]}{S_k^2 \left(\xi^2 S_k^2 - 2d |\xi| \sqrt{S_k^2} + d^2 \right)}. \quad (26)$$

For normally distributed data with $\theta = \sigma^2$, the Fisher information matrix is $I(\theta) = \frac{1}{2\sigma^4}$;

consequently, W_k^* can be written as

$$W_k^* = \frac{k \left(\ln \left[\left(d/\sqrt{S_k^2} - |\xi| \right)^2 / 9(1 + \xi^2) C_{pmk0}^2 \right] \right)^2}{\frac{\left[d \left(\sqrt{S_k^2} |\xi| - d \right) \right]^2}{\left[S_k^2 \left(S_k^2 \xi^2 - 2d |\xi| \sqrt{S_k^2} + d^2 \right) \right]^2} 2S_k^4}. \quad (27)$$

Therefore, given the value of α_s and the maximum allowable sample size n_0 , the test is performed by computing, for $k=2,3,\dots, n_0$, the statistic

$$\begin{aligned} W_k^{*(1)} &= \sqrt{k/n_0} W_k^* \\ &= \sqrt{k/n_0} \sqrt{\frac{k \left(\ln \left[\left(d/\sqrt{S_k^2} - |\xi| \right)^2 / 9(1 + \xi^2) C_{pmk0}^2 \right] \right)^2}{\frac{\left[d \left(\sqrt{S_k^2} |\xi| - d \right) \right]^2}{\left[S_k^2 \left(S_k^2 \xi^2 - 2d |\xi| \sqrt{S_k^2} + d^2 \right) \right]^2} 2S_k^4}}. \end{aligned} \quad (28)$$

Let n_{stop} be the first integer $k=2,3,\dots, n_0$ for which $W_k^{*(1)} > w_{\alpha_s}$:

- We reject H_0 if $W_k^{*(1)} > w_{\alpha_s}$ and n_{stop} is the stopping sample size of the test;
- We do not reject H_0 if $W_k^{*(1)}$ does not exceed w_{α_s} by n_0 and n_0 is the stopping sample size of the test;
- If $W_k^{*(1)}$ does not exceed w_{α_s} for $2 \leq k < n_0$, no decision can yet be made in favour of either of the two hypotheses and the decision is taken to continue observation.

In the case at hand, where $q=1$, the critical value w_{α_s} is obtained from the distribution of $\sup_{0 < t < 1} |B(t)|$.

Specifically, w_{α_s} is such that (Feller, 1970):

$$1 - \alpha_s = \frac{4}{\pi} \sum_{k=0}^{\infty} \frac{(-1)^k}{2k+1} \exp\left(\frac{-(2k+1)^2 \pi^2}{8w_{\alpha_s}^2}\right). \quad (29)$$

As an example, for $\alpha_s = 0.02, 0.05, 0.1$ and 0.2 , the values of w_{α_s} are 2.576, 2.241, 1.96 and 1.645 respectively.

In real applications, the parameter $\xi = (\mu - T)/\sigma$ is unknown and has to be estimated by substituting μ and σ with their estimators, i.e. $\hat{\xi} = (\bar{X}_k - T)/S_k$, and the statistics $W_k^{*(1)}$ should be calculated by substituting ξ with $\hat{\xi}$. We are aware that such an approach introduces a certain amount of variability. Therefore, for the sake of completeness, we will analyse the effects of ξ on the finite sample behaviour of the sequential test statistic in Section 7.

5. A sequential sampling plan for variables based on C_{pmk}

In order to compare the statistical properties of the sequential test with those of the PL-test, a suitable approach is to study the power functions of the tests under equal conditions.

Note that the sequential test is two sided with composite alternative hypothesis $H_1 : C_{pmk} \neq C_{pmk0}$, while the PL-test is unilateral. Thus, to correctly compare the two tests, cases under H_1 should be taken into consideration where $C_{pmk} = C_{pmk1}$ with $C_{pmk1} > C_{pmk0}$. In this manner, the sequential bilateral test with Type I error probability α_s can be compared with the non-sequential unilateral PL-test with Type I error probability equal to $\alpha_{PL} = \alpha_s / 2$.

Furthermore, as far as the sequential test is concerned, it is also important to consider:

- The role of the maximum allowable sample size n_0 , since it affects the statistical properties of the sequential test both under H_0 and H_1 ;
- The behaviour of the stopping sample size n_{stop} required by the sequential test in order to decide in favour of H_0 and H_1 .

This complex analysis can be developed by studying the use of the proposed sequential test in the framework of a variables sampling plan based on C_{pmk} . In such a way we can also propose a Sequential Sampling Plan (S-SP) based on C_{pmk} .

Wu and Pearn (2008) used several results from Pearn and Lin (2002) for developing a variables sampling plan (WP-SP) based on C_{pmk} . Their approach can be summarised as follows.

The acceptance sampling plan uses C_{pmk} as benchmark for lot sentencing. The criterion used for measuring the performance of the sampling plan is the operating characteristic (OC) curve which quantifies the risks for producers and consumers. In the WP-SP framework, the OC curve plots the probability of lot acceptance versus the values of the C_{pmk} index.

The acceptable quality level (AQL) and the lot tolerance percent defective (LTPD) are both defined in terms of the C_{pmk} index: C_{AQL} and C_{LTPD} respectively.

The WP-SP is defined by the sample size n and the critical acceptance value C_0 , and is such that for $C_{pmk} = C_{AQL}$ the producer's risk is α_{WP-SP} and for $C_{pmk} = C_{LTPD}$ the consumer's risk is β_{WP-SP} . Here, the producer's risk α_{WP-SP} is the probability of rejecting lots with $C_{pmk} \geq C_{AQL}$, and the consumer's risk β_{WP-SP} is the probability of accepting lots with $C_{pmk} \leq C_{LTPD}$. In other words, the two points of interest on the OC curve are $(C_{AQL}, 1 - \alpha_{WP-SP})$ and $(C_{LTPD}, \beta_{WP-SP})$.

Based on a sample of size n , a value of \hat{C}_{pmk} (6) is calculated: if $\hat{C}_{pmk} > C_0$ the lot is accepted, otherwise the lot is rejected.

This sampling plan is equivalent to a PL-test with sample size n and critical value C_0 for testing $H_0 : C_{pmk} \leq C_{LTPD}$ versus $H_1 : C_{pmk} > C_{LTPD}$. With these parameters (n and C_0), when $C_{pmk} = C_{LTPD}$ the first error probability of the PL-test is $\alpha_{PL} = \beta_{WP-SP}$, and for $C_{pmk} = C_{AQL}$ the power function of the PL-test (9) is $\pi_{PL}(C_{AQL}) = \Pr(\hat{C}_{pmk} \geq C_0 | C_{pmk} = C_{AQL}) = 1 - \alpha_{WP-SP}$.

Wu and Pearn (2008), assuming ξ as known and equal to $\xi = 0.5$, computed and tabulated the critical acceptance values C_0 and the sample sizes n of the sampling plan for several values of α_{WP-SP} and β_{WP-SP} , with various benchmarking quality levels $(C_{AQL}, C_{LTPD}) = (1.33, 1.00), (1.50, 1.00), (1.50, 1.33), (1.67, 1.33), (1.67, 1.50), (2.00, 1.67)$.

Given the equivalence, explained above, between the PL-test and the sequential test, we are now able to propose a sequential sampling plan (S-SP) equivalent and comparable to the WP-SP.

The S-SP based on the statistic $W_k^{*(1)}$ (28) can be set up with a critical value $w_{\beta_{S-SP}}$ with $\beta_{S-SP} = \alpha_S = 2\alpha_{PL}$, and is performed as follows.

Let n_{stop} be the first integer $k=2,3,\dots, n_0$ for which $W_k^{*(1)} > w_{\beta_{S-SP}}$:

- We accept the lot (we reject $H_0 : C_{pmk} = C_{LTPD}$) if $W_{n_{stop}}^{*(1)} > w_{\beta_{S-SP}}$ and n_{stop} is the stopping sample size of the sampling plan;
- We reject the lot (we do not reject H_0) if $W_k^{*(1)}$ does not exceed $w_{\beta_{S-SP}}$ by n_0 ;
- If $W_k^{*(1)}$ does not exceed $w_{\beta_{S-SP}}$ for $2 \leq k < n_0$, no decision can be made on the lot and the decision is taken to continue the inspection.

6. The Simulation Study

To properly compare the properties of the sequential test with those of the PL-test, the performance of the proposed sequential method should be evaluated in a worst-case scenario. However, we need an initial benchmark since, at this stage of the research, the statistical properties of the sequential procedure are unknown.

To this end, the properties of the sequential test under H_0 and H_1 , or equivalently the properties of the S-SP, are studied under several scenarios by means of simulation studies (details on how the scenarios were constructed are given in Appendix B). Please note that in all the simulations that follow, we set $\xi = 0.5$ for the sequential test. In such a way, with regard to this aspect, we use the same setting as the PL-test. Hence, on the basis of the results obtained a further simulation study will be carried out to identify a value for ζ that can represent the most unfavourable condition for the sequential procedure.

As a first step, we study the performance of the sequential sampling plan in connection with the consumer's risk, or equivalently the performance of the sequential test under $H_0 : C_{pmk} = C_{LTPD}$.

With this aim, for each combination of C_{LTPD} (1.00, 1.33, 1.50, 1.67), and β_{S-SP} (0.02, 0.05, 0.1) we generated, using *R* (*R* Core Team 2020), $5 \cdot 10^4$ replicates from a normally distributed process. The aim of these simulations was to determine the smallest maximum allowable sample size, $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}$,

which gives an empirical consumer's risk $\hat{\beta}_{S-SP}$ smaller than the nominal β_{S-SP} value: $\hat{\beta}_{S-SP} < \beta_{S-SP}$.

Or, equivalently, to determine the smallest maximum allowable sample size, $n_{0;\hat{\alpha}_S < \alpha_S}$, which gives an empirical type I error probability $\hat{\alpha}_S$ smaller than the nominal α_S value: $\hat{\alpha}_S < \alpha_S$. The empirical consumer's risk is estimated as the proportion of accepted lots when $C_{pmk} = C_{LTPD}$ (the proportion of correctly accepted $H_0 : C_{pmk} = C_{LTPD}$).

In greater detail, in order to obtain $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}$, we implemented an iterative search algorithm with initial value for $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}$ denoted by n_{start} . The algorithm works as follows:

1. With n_{start} as the maximum allowable sample size of the sequential test, the value of $\hat{\beta}_{S-SP}$ is estimated as the fraction of correctly accepted $H_0 : C_{pmk} = C_{LTPD}$ over $m = 5 \cdot 10^4$ simulations;
2. If

$$0 < \frac{\beta_{S-SP} - \hat{\beta}_{S-SP}}{\beta_{S-SP}} \leq 0.025,$$

then $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}$ is set equal to n_{start} and the search algorithm stops;

3. Otherwise, if $\hat{\beta}_{S-SP} > \beta_{S-SP}$, then $n_{start} = n_{start} + 1$; if $\hat{\beta}_{S-SP} < \beta_{S-SP}$, then $n_{start} = n_{start} - 1$ and the algorithm starts a further m simulations.

The simulation results are summarized in Table 1 (rows with white background), where for each combination of β_{S-SP} and C_{LTPD} , the following quantities are given:

- $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}$ the smallest maximum allowable sample size for sequential sampling plan for achieving an empirical consumer's risk $\hat{\beta}_{S-SP}$ smaller than the nominal value β_{S-SP} ($\hat{\beta}_{S-SP} < \beta_{S-SP}$); or equivalently, the smallest maximum allowable sample size for the sequential test for achieving an empirical type I error probability $\hat{\alpha}_s$ smaller than the nominal α_s value ($\hat{\alpha}_s < \alpha_s$);
- $\hat{\beta}_{S-SP}$ the empirical consumer's risk.

C_{LTPD}	$\beta_{S-SP} = 0.1$		$\beta_{S-SP} = 0.05$		$\beta_{S-SP} = 0.02$	
	$n_{0; \hat{\beta}_{S-SP} < \beta_{S-SP}}$	$\hat{\beta}_{S-SP}$	$n_{0; \hat{\beta}_{S-SP} < \beta_{S-SP}}$	$\hat{\beta}_{S-SP}$	$n_{0; \hat{\beta}_{S-SP} < \beta_{S-SP}}$	$\hat{\beta}_{S-SP}$
1.00	158	0.0995	200	0.0487	331	0.0194
	172	0.0998	242	0.0495	359	0.0193
1.33	149	0.0987	198	0.0497	296	0.0199
	161	0.0992	232	0.0499	324	0.0199
1.50	153	0.0996	213	0.0492	319	0.0198
	175	0.0993	240	0.0499	320	0.0199
1.67	147	0.0995	197	0.0497	258	0.0199
	157	0.0999	219	0.0498	288	0.0197

Table 1. Simulation results for $C_{pmk} = C_{LTPD}$: $n_{0; \hat{\beta}_{S-SP} < \beta_{S-SP}}$ and $\hat{\beta}_{S-SP}$ (white background for $\xi = 0.5$; shaded background for $\xi = 3$)

The R code for reproducing the simulation study for the case $C_{LTPD} = 1.50$ and $\beta_{S-SP} = 0.05$ is provided as Supplementary Information (SH0_150.R for $\xi = 0.5$ and SH0_150N3.R for $\xi = 3$).

As a second step we study the statistical properties of the S-SP in connection with the producer's risk, or equivalently the statistical properties of the sequential test under H_1 ($C_{pmk} = C_{AQL}$).

With this aim, for the benchmarking quality levels $(C_{AQL}, C_{LTPD}) = (1.33, 1.00), (1.50, 1.00), (1.50, 1.33), (1.67, 1.33), (1.67, 1.50), (2.00, 1.67)$ and for producer's risk $\alpha_{S-SP} = \alpha_{WP-SP} = (0.01, 0.025, 0.05)$, we looked for the maximum allowable sample size n_0 required by the S-SP that for $C_{pmk} = C_{AQL}$ allows to achieving the same producer's risk as the WP-SP. More precisely for each value of α_{S-SP} , β_{S-SP} , C_{AQL} , C_{LTPD} we used a simulation experiment to determine the smallest maximum allowable sample size, $n_{0; \hat{\pi}_S > 1 - \alpha_{S-SP}}$, which gives an empirical power of the sequential test $\hat{\pi}_S$ greater than $1 - \alpha_{S-SP}$, or equivalently to obtain an empirical producer's risk $\leq \alpha_{S-SP}$. The empirical power $\hat{\pi}_S$ of

the sequential test is estimated as the proportion of correctly rejected $H_0 : C_{pmk} = C_{LTPD}$ when $C_{pmk} = C_{AQL}$.

In order to obtain $n_{0;\hat{\pi}_S > 1 - \alpha_{S-SP}}$ we implemented an iterative search algorithm with an initial value for $n_{0;\hat{\pi}_S > 1 - \alpha_{S-SP}}$ denoted by n_{start} . The algorithm works as follows:

1. With n_{start} as the maximum allowable sample size of the sequential test, the empirical power of the test $\hat{\pi}_S$ is estimated as the proportion of correctly rejected H_0 over $m = 5 \cdot 10^4$ simulations;

2. If

$$0 < \frac{\hat{\pi}_S - (1 - \alpha_{S-SP})}{1 - \alpha_{S-SP}} \leq 0.025,$$

then $n_{0;\hat{\pi}_S > 1 - \alpha_{S-SP}}$ is set equal to n_{start} and the search algorithm stops. At the same time the average stopping sample size n_{avg} was empirically assessed as the average of the stopping sample sizes n_{stop} required by the sequential test to correctly reject H_0 (to accept the lot when $C_{pmk} = C_{AQL}$) when the maximum allowable sample size is equal to $n_{0;\hat{\pi}_S > 1 - \alpha_{S-SP}}$;

3. Otherwise, if $\hat{\pi}_S \leq 1 - \alpha_{S-SP}$, then $n_{start} = n_{start} + 1$; if $\hat{\pi}_S > 1 - \alpha_{S-SP}$, then $n_{start} = n_{start} - 1$ and the algorithm starts other m simulations.

The simulation results are summarized in Tables 2-7 (rows with white background). For each combination of α_{S-SP} , β_{S-SP} , C_{AQL} and C_{LTPD} , the following quantities are given: $n_{0;\hat{\pi}_S > 1 - \alpha_{S-SP}}$ the smallest maximum allowable sample size for the sequential test for achieving an empirical power $\hat{\pi}_S > 1 - \alpha_{S-SP}$ (or equivalently an empirical producer's risk $\hat{\alpha}_{S-SP}$ smaller than or equal to the nominal value α_{S-SP}); n_{avg} the average of the stopping sample sizes n_{stop} required for the sequential test with maximum allowable sample size $n_{0;\hat{\pi}_S > 1 - \alpha_{S-SP}}$ for concluding in favour of H_1 ; S.D.(n_{stop}) the standard deviation of the final sample sizes n_{stop} ; $\hat{\alpha}_{S-SP} = 1 - \hat{\pi}_S$ the estimated producer's risk. In order to allow comparisons, the parameters of the corresponding WP-SP (Wu and Pearn 2008) are also given in Tables 2-7.

The R code for reproducing the simulation study for the case $C_{AQL} = 1.50$, $C_{LTPD} = 1.33$, $\alpha_{WP-SP} = 0.01$ and $\beta_{WP-SP} = 0.01$ is provided as Supplementary Information (PS133_150_002.R for $\xi = 0.5$, and PS133_150_002N3.R for $\xi = 0.3$).

$C_{AQL} = 1.33 \quad C_{LTPD} = 1.00$						
α_{WP-SP}	β_{WP-SP}	n	C_0	$n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$	$n_{avg}(SD)$	$\hat{\alpha}_{S-SP}$
0.010	0.010	202	1.1634	165	87.31(25.52)	0.0097
				209	109.28(32.24)	0.0093
	0.025	170	1.1497	139	68.72(22.44)	0.0093
				176	86.56(28.69)	0.0094
	0.050	144	1.1360	120	55.10(20.19)	0.0097
				153	69.36(25.60)	0.0094
0.025	0.010	174	1.1779	141	79.38(23.08)	0.0243
				176	98.73(29.24)	0.0248
	0.025	144	1.1642	117	62.12(24.43)	0.0238
				148	77.56(25.99)	0.0237
	0.050	120	1.1504	98	48.49(18.05)	0.0243
				125	61.22(23.08)	0.0239
0.050	0.010	151	1.1925	119	71.15(20.52)	0.0498
				152	89.89(26.43)	0.0496
	0.025	123	1.1792	98	55.06(18.13)	0.0492
				125	69.35(23.04)	0.0479
	0.050	102	1.1654	81	42.40(16.06)	0.0496
				104	53.79(20.34)	0.0478

Table 2. WP-SP (n and C_0) and S-SP simulation results ($n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$, n_{avg} and SD) for $C_{AQL} = 1.33$ and $C_{LTPD} = 1.00$. (white background for $\xi = 0.5$; shaded background for $\xi = 3$)

$C_{AQL} = 1.50 \quad C_{LTPD} = 1.00$						
α_{WP-SP}	β_{WP-SP}	n	C_0	$n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$	$n_{avg}(SD)$	$\hat{\alpha}_{S-SP}$
0.010	0.010	98	1.2466	78	41.04(12.41)	0.0098
				98	50.54(15.50)	0.0091
				66	32.15(11.17)	0.0089
	0.025	82	1.2261	83	39.88(13.98)	0.0096
				56	25.12(10.22)	0.0092
	0.050	70	1.2057	70	31.17(12.63)	0.0099
0.025	0.010	85	1.2688	66	37.01(11.33)	0.0246
				82	45.54(14.23)	0.0248
				55	28.58(10.25)	0.0243
	0.025	70	1.2484	68	35.22(12.56)	0.0247
				46	21.78(9.27)	0.0242
	0.050	58	1.2279	58	27.44(11.50)	0.0242
0.050	0.010	74	1.2913	56	33.07(10.20)	0.0499
				70	40.90(12.80)	0.0491
				46	25.15(9.28)	0.0464
	0.025	60	1.2714	57	30.93(11.32)	0.0494
				38	18.89(8.37)	0.0463
	0.050	50	1.2511	47	23.34(10.14)	0.0499

Table 3. WP-SP (n and C_0) and S-SP simulation results ($n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$, n_{avg} and SD) for $C_{AQL} = 1.50$ and $C_{LTPD} = 1.00$ (white background for $\xi = 0.5$; shaded background for $\xi = 3$).

$C_{AQL} = 1.50 \quad C_{LTPD} = 1.33$						
α_{WP-SP}	β_{WP-SP}	n	C_0	$n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$	$n_{avg}(SD)$	$\hat{\alpha}_{S-SP}$
0.010	0.010	1039	1.4147	925	493.71(136.34)	0.0098
				1116	597.40(167.28)	0.0098
				790	394.41(122.54)	0.0099
	0.025	877	1.4075	963	480.48(149.80)	0.0098
				678	318.17(109.64)	0.0096
	0.050	749	1.4003	819	386.17(133.97)	0.0099
0.025	0.010	887	1.4220	782	447.67(123.85)	0.0235
				957	544.40(152.62)	0.0249
				658	354.10(109.53)	0.0249
	0.025	738	1.4149	805	431.19(134.42)	0.0248
				561	283.34(97.74)	0.0248
	0.050	621	1.4076	688	346.79(120.44)	0.0245
0.050	0.010	765	1.4295	675	408.00(111.02)	0.0494
				819	493.67(135.81)	0.0498
				563	319.47(98.01)	0.0469
	0.025	627	1.4224	678	386.57(118.41)	0.0498
				472	253.30(86.21)	0.0485
	0.050	520	1.4152	571	306.21(105.58)	0.0494

Table 4. WP-SP (n and C_0) and S-SP simulation results ($n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$, n_{avg} and SD) for $C_{AQL} = 1.50$ and $C_{LTPD} = 1.33$ (white background for $\xi = 0.5$; shaded background for $\xi = 3$).

$C_{AQL} = 1.67 \quad C_{LTPD} = 1.33$						
α_{WP-SP}	β_{WP-SP}	n	C_0	$n_{0;\hat{\pi}_S>1-\alpha_{S-SP}}$	$n_{avg}(SD)$	$\hat{\alpha}_{S-SP}$
0.010	0.010	286	1.4988	250	133.04(37.91)	0.0092
				301	159.36(46.00)	0.0097
	0.025	240	1.4846	212	105.33(33.76)	0.0095
				254	125.99(40.76)	0.0097
	0.050	204	1.4704	182	84.51(30.15)	0.0092
				221	101.70(36.42)	0.0099
0.025	0.010	245	1.5137	212	120.18(34.38)	0.0240
				253	143.61(41.25)	0.0249
	0.025	203	1.4995	177	94.40(30.32)	0.0241
				214	113.43(36.79)	0.0244
	0.050	170	1.4852	151	75.25(27.11)	0.0235
				180	89.77(32.33)	0.0244
0.050	0.010	213	1.5287	183	109.31(30.92)	0.0493
				218	130.51(37.20)	0.0495
	0.025	174	1.5149	149	84.32(26.91)	0.0486
				179	101.01(32.35)	0.0499
	0.050	143	1.5006	122	64.95(23.23)	0.0498
				150	79.22(28.63)	0.0494

Table 5. WP-SP (n and C_0) and S-SP simulation results ($n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$, n_{avg} and SD) for $C_{AQL} = 1.67$ and $C_{LTPD} = 1.33$ (white background for $\xi = 0.5$; shaded background for $\xi = 3$).

$C_{AQL} = 1.67 \quad C_{LTPD} = 1.50$						
α_{WP-SP}	β_{WP-SP}	n	C_0	$n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$	$n_{avg}(SD)$	$\hat{\alpha}_{S-SP}$
0.010	0.010	1253	1.5847	1160	615.52(170.65)	0.0080
				1359	726.96(203.51)	0.0090
	0.025	1058	1.5775	975	489.08(151.33)	0.0094
				1158	581.11(180.28)	0.0094
	0.050	904	1.5703	842	394.67(135.05)	0.0097
				1004	471.38(161.65)	0.0097
0.025	0.010	1068	1.5921	966	552.49(152.79)	0.0231
				1161	662.10(184.15)	0.0234
	0.025	890	1.5849	813	438.64(135.03)	0.0249
				970	523.44(162.42)	0.0248
	0.050	749	1.5776	690	349.80(119.41)	0.0247
				827	417.75(143.83)	0.0249
0.050	0.010	922	1.5995	840	507.27(137.42)	0.0471
				993	598.93(164.08)	0.0491
	0.025	756	1.5924	686	393.65(119.22)	0.0498
				820	467.16(143.15)	0.0493
	0.050	627	1.5852	574	310.70(105.14)	0.0489
				690	370.31(125.80)	0.0497

Table 6. WP-SP (n and C_0) and S-SP simulation results ($n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$, n_{avg} and SD) for $C_{AQL} = 1.67$ and $C_{LTPD} = 1.50$ (white background for $\xi = 0.5$; shaded background for $\xi = 3$).

$C_{AQL} = 2.00 \quad C_{LTPD} = 1.67$						
α_{WP-SP}	β_{WP-SP}	n	C_0	$n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$	$n_{avg}(SD)$	$\hat{\alpha}_{S-SP}$
0.010	0.010	426	1.8341	388	206.69(58.18)	0.0097
				453	241.81(68.06)	0.0084
	0.025	359	1.8203	331	165.06(51.71)	0.0097
				388	192.88(61.02)	0.0095
	0.050	305	1.8065	287	133.58(46.66)	0.0099
				333	154.68(54.50)	0.0096
0.025	0.010	365	1.8485	331	188.48(52.83)	0.0247
				383	218.14(61.57)	0.0239
	0.025	303	1.8347	276	148.07(46.71)	0.0243
				323	172.43(64.72)	0.0236
	0.050	254	1.8207	233	117.29(41.25)	0.0246
				275	137.70(48.47)	0.0247
0.050	0.010	316	1.8630	281	169.82(46.92)	0.0493
				331	198.42(55.42)	0.0489
	0.025	258	1.8495	233	148.07(41.33)	0.0497
				274	155.14(48.74)	0.0491
	0.050	213	1.8356	195	104.19(36.37)	0.0497
				228	121.36(42.71)	0.0497

Table 7: WP-SP (n and C_0) and S-SP simulation results ($n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$, n_{avg} and SD) for $C_{AQL} = 2.00$ and $C_{LTPD} = 1.67$ (white background for $\xi = 0.5$; shaded background for $\xi = 3$).

7 Discussion

Before drawing any conclusions, it is important to deal with the relevant issue introduced in the previous Section. For the purposes of comparison with the PL-test, the results for the sequential test (Tables 1-7 rows with white background) were obtained by assuming ξ as being known and equal to 0.5.

However, in real-world applications, ξ is unknown. Furthermore, for the PL-test and the WP-SP by setting $\xi = 0.5$ conservative sample size and critical values were obtained, whereas the effect of ξ on the statistical properties of the sequential test is unknown.

Therefore, in order to evaluate the impact of ξ on the sequential test, or equivalently on the sequential sampling plan, and identify a value of ξ that can reasonably represent the worst-case scenario, we conducted further simulation studies.

For each combination of α_s , C_{pmk0} (C_{LTPD}), we considered values of ξ ranging from 0 to 5 ($\xi = 0, 0.5, 1.0, 2.0, 3.0, 5.0$), and we simulated 10^4 observations from processes with $C_{pmk} \geq C_{pmk0}$ (for example if $C_{pmk0} = 1.67$ we considered $C_{pmk} = 1.67(0.05)2.12$).

The aim of these simulations was to evaluate the empirical power $\hat{\pi}_s$ of the sequential test estimated as the proportion of rejected H_0 . As an example, Figure 1 plots $\hat{\pi}_s$ for the case $C_{pmk0} = 1.67$ and $\alpha_s = 0.02$ versus the values of $C_{pmk} = 1.67(0.05)2.12$.

The curves are plotted for each value of ξ , with the addition of the bold curve for $\xi = 0.5$ and a dashed red curve for $\xi = 3$.

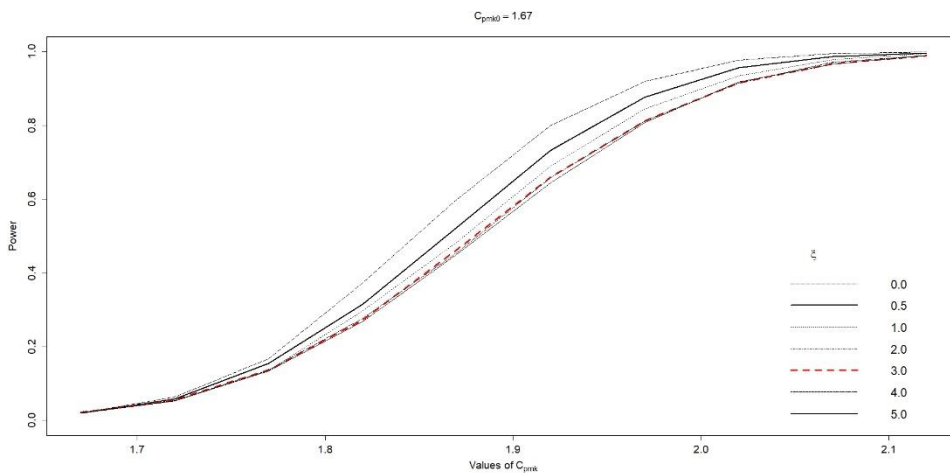


Figure 1. Empirical power functions for the case $\alpha_s = 0.02$ and $C_{pmk0} = 1.67$ for ξ from 0 to 5

For completeness, in Figures 2-4 we reported the results for all the cases examined where for clearness purpose, we limit the curves plotted to $\xi = (0.5, 3.0, 4.0, 5.0)$.

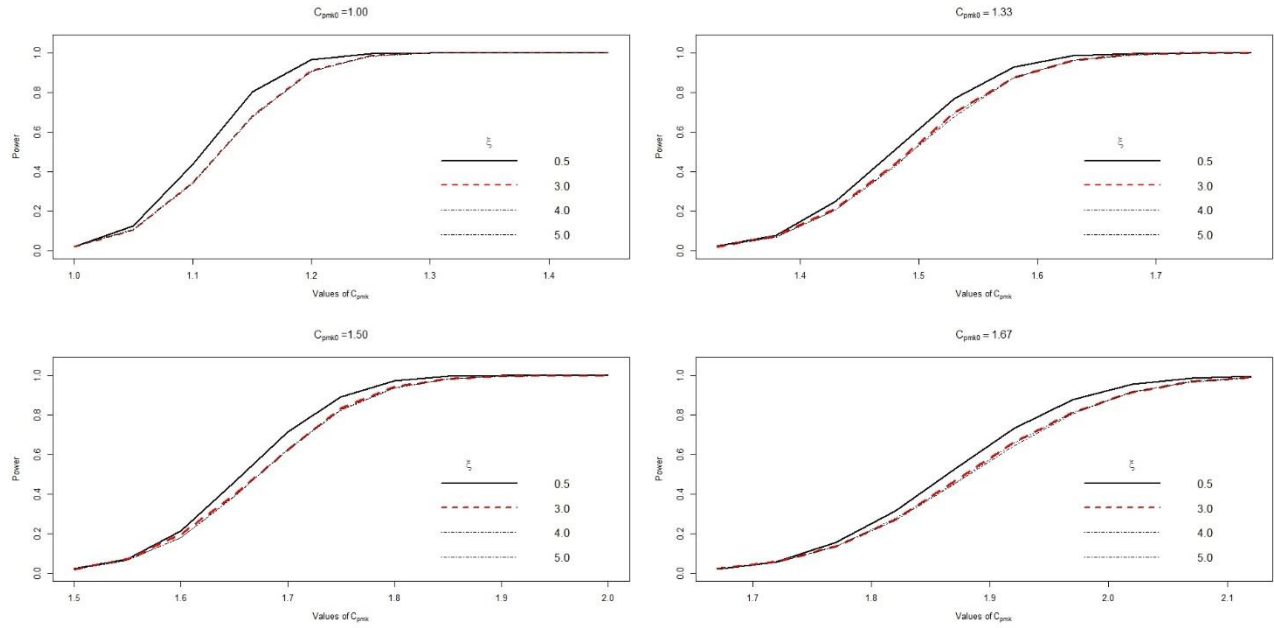


Figure 2. Empirical power functions for the case $\alpha_S = 0.02$ and $C_{pmk0} = (1.00, 1.33, 1.50, 1.67)$ for $\xi = (0.5, 3.0, 4.0, 5.0)$

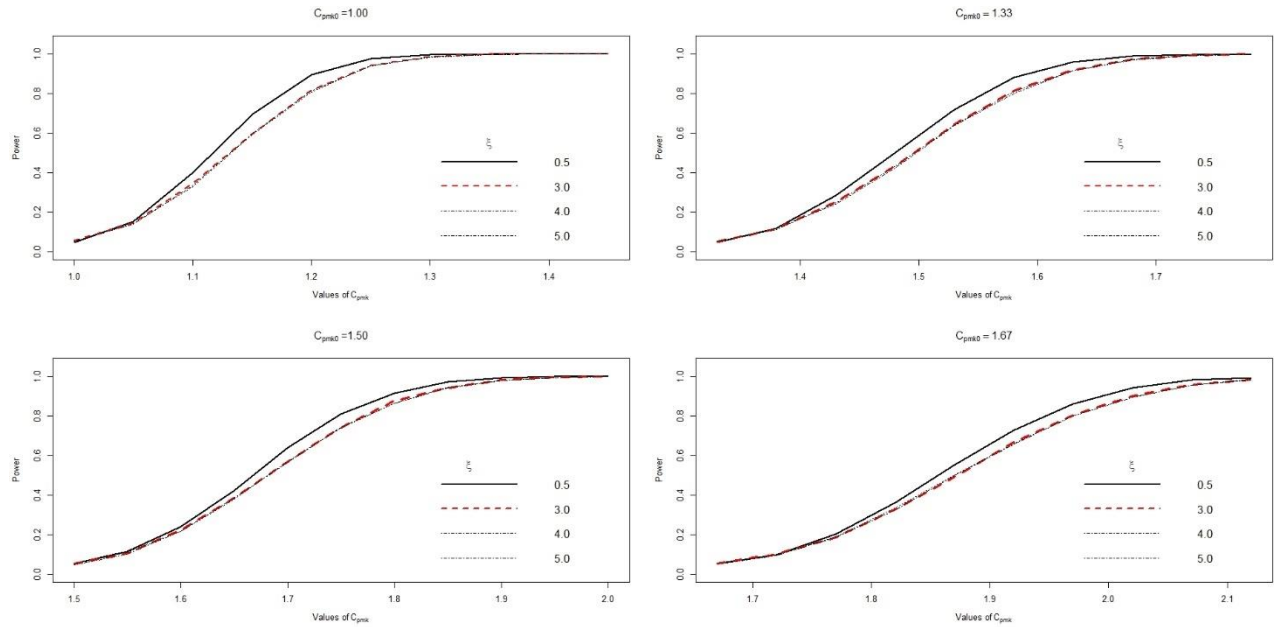


Figure 3. Empirical power functions for the case $\alpha_S = 0.05$ and $C_{pmk0} = (1.00, 1.33, 1.50, 1.67)$ for $\xi = (0.5, 3.0, 4.0, 5.0)$

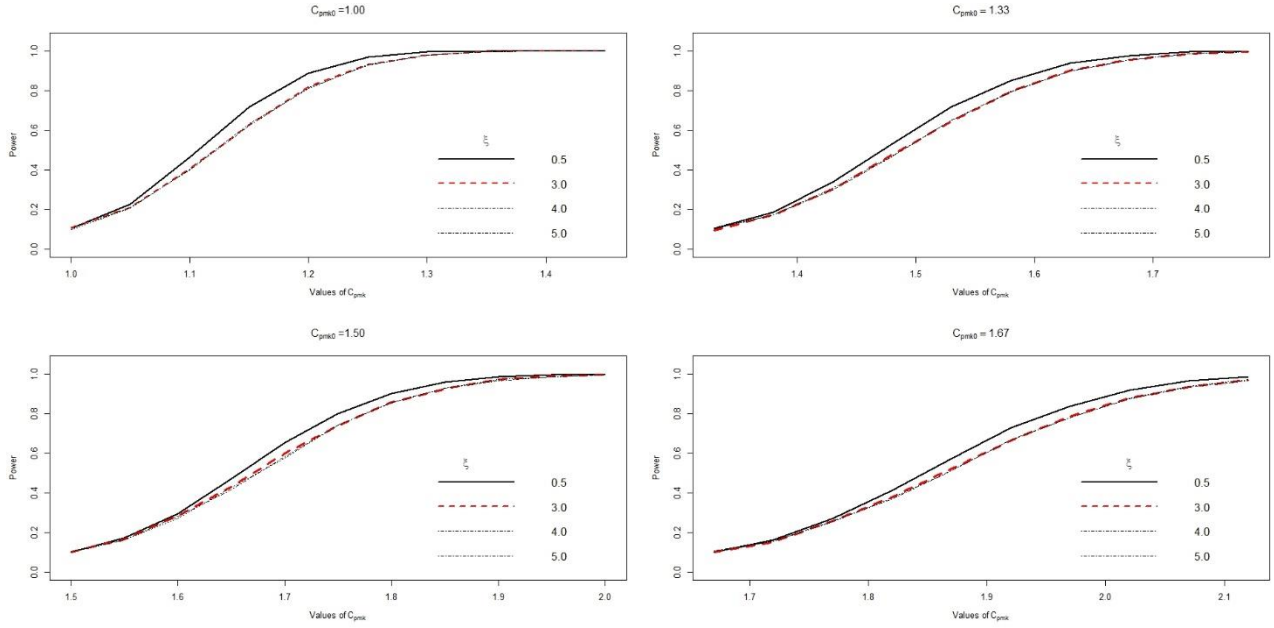


Figure 4. Empirical power functions for the case $\alpha_s = 0.1$ and $C_{pmk0} = (1.00, 1.33, 1.50, 1.67)$ for $\xi = (0.5, 3.0, 4.0, 5.0)$

By examining the results, it can be noted that the empirical power functions $\hat{\pi}_s$ decrease as ξ increases and that the changes for $\xi \geq 3$ are negligible. Hence, considering also that in literature (Wu and Pearn, 2008, Lepore et al. 2017) the range usually considered to study the effects of ξ is $0 \leq \xi \leq 3$ and that these values cover a wide range of real situations, the value $\xi = 3$ can reasonably represent a pessimistic situation for the sequential procedures.

Thus, to study the performance of the sequential sampling plan in connection with the consumer's risk, or equivalently the performance of the sequential test under $H_0: C_{pmk} = C_{LTPD}$ in the worst-case scenario, we repeated with $\xi = 3$ the simulation experiment described in Section 6. In such a way, for each combination of β_{S-SP} and C_{LTPD} , we obtain the values of $n_{0; \hat{\pi}_s < \beta_{S-SP}}$ and $\hat{\beta}_{S-SP}$. The simulation results are summarized in Table 1 (rows with shaded background). Similarly, to study the statistical properties of the S-SP in connection with the producer's risk, or equivalently the statistical properties of the sequential test under $H_1 (C_{pmk} = C_{AQL})$, in the worst-case scenario, we repeated with $\xi = 3$ the simulation experiment described in Section 6. The results concerning the values $n_{0; \hat{\pi}_s > 1 - \alpha_{S-SP}}$, n_{avg} and $\hat{\alpha}_{S-SP}$ are reported in Tables 2-7 (rows with shaded background).

Therefore, by examining Tables 2-7 it is possible to quantify the changes occurred in the performance of the sequential test, moving from a situation with $\xi = 0.5$ to a situation with $\xi = 3$ and the following

discussion will be made by comparing the outcomes in the worst-case scenario of the sequential procedures with the performance of the PL test.

The results indicate that, when the capability requirements C_{AQL} and C_{LTPD} are high ($C_{LTPD} \geq 1.33$), the S-SP allows, on average, a considerable reduction in sample size compared to the WP-SP.

As an example, for $C_{LTPD}=1.33$ and $C_{AQL}=1.50$ with producer's risk $\alpha_{WP-SP}=0.01$ and consumer's risk $\beta_{WP-SP}=0.01$, the WP sampling plan requires a sample size of $n=1039$ with a critical value $C_0=1.4147$ (Table 4). The S-SP:

- When $C_{pmk} = C_{AQL}=1.50$, with a maximum allowable sample size equal to $n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}=1116$, the estimated producer's risk is equal to $\hat{\alpha}_{S-SP}=0.0098$ with $n_{avg} \cong 597$ (Table 4);
- When $C_{pmk} = C_{LTPD}=1.33$ (Table 1), the smallest maximum allowable sample size required by the sequential test to ensure an estimated consumer's risk $\hat{\beta}_{S-SP}$ smaller than the nominal value β_{S-SP} is $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}=324$.

Therefore, in this case the S-SP: for high-quality lots ($C_{pmk} = C_{AQL}$) allows, on average, a 42.54% reduction in sample size compared to the WP-SP ($n_{avg} \cong 597$); for low-quality lots ($C_{pmk} = C_{LTPD}$) allows a 68.82% reduction in sample size compared to the WP-SP, since it rejects the lot using a sample size not greater than $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}=324$.

For $C_{LTPD}=1.67$ and $C_{AQL}=2.00$ with $\alpha_{WP-SP}=0.025$ and $\beta_{WP-SP}=0.05$, the WP sampling plan has a sample size $n=254$ with a critical value $C_0=1.8207$ (Table 7). The S-SP:

- When $C_{pmk} = C_{AQL}=2.00$, with a maximum allowable sample size equal to $n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}=275$, has an estimated producer's risk equal to $\hat{\alpha}_{S-SP}=0.0247$ with $n_{avg} \cong 137.70$ (Table 7);
- When $C_{pmk} = C_{LTPD}=1.67$ (Table 1), the smallest maximum allowable sample size required by the sequential test to ensure an estimated consumer's risk $\hat{\beta}_{S-SP}$ smaller than the nominal value β_{S-SP} is $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}=157$ (Table 1).

In this case, the S-SP: for high-quality lots ($C_{pmk} = C_{AQL}$) allows, on average, a 45.7% reduction in sample size compared to the WP-SP ($n_{avg} \cong 138$); for low-quality lots ($C_{pmk} = C_{LTPD}$) allows a 38.2% reduction in sample size compared to the WP-SP, since it rejects the lot using a sample size not greater than $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}=157$.

However, for the sake of completeness, it is important to note that the sequential sampling plan, in order to ensure that the empirical consumer's risk does not exceed the nominal level β_{S-SP} , requires at a minimum the sequential inspection of a number of units not less than the values given in Table 1 (rows with shaded background).

By comparing the values of $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}$, given in Table 1, with the sample sizes of an equivalent WP-SP, we find that the sequential sampling plan can have lower performance than the WP-SP when the capability requirements are low ($C_{LTPD} < 1.33$).

As an example, for $C_{LTPD}=1.00$ and $C_{AQL}=1.33$ with $\alpha_{WP-SP}=0.025$ and $\beta_{WP-SP}=0.025$, the WP sampling plan has a sample size $n=144$ with a critical value $C_0=1.1642$ (Table 2).

The SSP:

- When $C_{pmk} = C_{AQL}=1.33$, with a maximum allowable sample size equal to $n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}=148$, has an estimated producer's risk equal to $\hat{\alpha}_{S-SP}=0.0237$ with $n_{avg} \cong 77.56$ (Table 2);
- When $C_{pmk} = C_{LTPD}=1.00$, the smallest maximum allowable sample size required by the sequential test to ensure an estimated consumer's risk $\hat{\beta}_{S-SP}$ smaller than the nominal value β_{S-SP} is $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}=242$ (Table 1).

In this case $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}=242$ is larger than $n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}=148$; consequently, to ensure that the both the risks $\hat{\beta}_{S-SP}$ and $\hat{\alpha}_{S-SP}$ do not exceed their nominal values, β_{S-SP} and α_{S-SP} respectively, it is necessary to set up the sequential sampling plan using, as maximum sample size, the largest between $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}$ and $n_{0;\hat{\pi}_S > 1-\alpha_{S-SP}}$. Therefore, this is a scenario in which the S-SP requires a maximum sample size (242) larger than the sample size (144) required by WP-SP. In particular, the S-SP provides lower performance than the WP-SP for low-quality lots $C_{pmk} = C_{LTPD}$.

In examining the results, we can state that the sequential sampling plan provides lower performance than the WP-SP only for low capability requirements ($C_{LTPD} < 1.33$) and limited to the case $C_{LTPD} = 1.33$ and $C_{AQL}=1.67$ with:

- $\beta_{WP-SP}=0.01$ for which the S-SP requires a sample size at least equal to $n_{0;\hat{\beta}_{S-SP} < \beta_{S-SP}}=324$ (Table 1), while the parameters of the WP-SP are $n=286$ and $C_0=1.4988$ for $\alpha_{WP-SP}=0.01$, $n=245$ and $C_0=1.5137$ for $\alpha_{WP-SP}=0.025$ and $n=213$ and $C_0=1.587$ for $\alpha_{WP-SP}=0.05$, respectively (Table 5);

- $\beta_{WP-SP}=0.025$ for which the S-SP requires a sample size at least equal to $n_{0;\hat{\beta}_{S-SP}<\beta_{S-SP}}=232$ (Table 1) while the parameters of the WP-SP are $n=203$ and $C_0=1.4995$ $\alpha_{WP-SP}=0.025$ (Table 5) and $n=174$ and $C_0=1.5149$ for $\alpha_{WP-SP}=0.050$ (Table 5);
- $\beta_{WP-SP}=0.05$ for which the S-SP requires a sample size at least equal to $n_{0;\hat{\beta}_{S-SP}<\beta_{S-SP}}=161$ (Table 1) while the parameters of the WP-SP are $n=143$ and $C_0=1.5006$ for $\alpha_{WP-SP}=0.050$ (Table 5).

8. Concluding Remarks

In this article, we propose a sequential test for the process capability index C_{pmk} . The study of the statistical properties of the proposed test is complex task as it is necessary to consider several aspects jointly. For this reason, a sequential sampling plan is also proposed, which makes it possible to study the performance of the sequential procedures and compare them with the corresponding non-sequential methodologies in a more intuitive manner.

More precisely, we studied the statistical properties of the sequential test and the sequential sampling plan with an extensive simulation study with regard to the type I error (the consumer's risk of the sampling plan), the average of the sample sizes for correctly deciding, for H_0 and H_1 , and the maximum allowable sample size required to achieve a predetermined power level (the producer's risk of the sampling plan).

We compared the performance of the sequential procedures with that of the PL-test and WP-SP.

The results showed that, for high quality requirements such as $C_{LTPD}>1.33$, the S-SP allows, on average, a considerable reduction in sampling size compared to the WP-SP (or equivalently the sequential test for $C_{pmk0}>1.33$ allows, on average, smaller stopping sample sizes compared to the fixed sample size tests, while maintaining the desired α -level and power).

In summary, the proposed sequential procedures have several interesting features: they may offer a substantial decrease in sample size compared to the non-sequential methods, while type I and II error probabilities are correctly maintained at their desired values.

We consider these results to be valuable, because in a highly competitive context where both cost and quality are relevant, the availability of statistical methods which make it possible to reduce sampling size can be directly translated into resource and cost savings.

Appendix A: Conditions C1-C9

Conditions C1-C7 are the usual requirements (Serfling 1980) for the existence of maximum likelihood estimators. Bhattacharya et al. (2016) showed that these condition are met for X normally distributed.

Condition C8 holds.

Proof.

Let us consider the general case where we have

$$f(x, \theta) = \frac{1}{\sqrt{2\pi\sigma^2}} \exp\left(-\frac{1}{2\sigma^2}(x - \mu)^2\right),$$

with $\theta = (\mu, \sigma^2)$ and therefore

$$\ln f(x, \theta) = -\frac{1}{2} \ln 2\pi - \frac{1}{2} \ln \sigma^2 - \frac{1}{2\sigma^2}(x - \mu)^2.$$

The partial derivatives are of $\ln f(x, \theta)$ are

$$\frac{\partial \ln f(x, \theta)}{\partial \mu} = \frac{x - \mu}{\sigma^2}$$

and

$$\frac{\partial \ln f(x, \theta)}{\partial \sigma^2} = -\frac{1}{2\sigma^2} + \frac{1}{2\sigma^4}(x - \mu)^2,$$

respectively.

We have to demonstrate that

$$E_\theta \left| \frac{\partial \ln f(x, \theta)}{\partial \mu} \right|^{2+\delta} < \infty \quad (30)$$

and

$$E_\theta \left| \frac{\partial \ln f(x, \theta)}{\partial \sigma^2} \right|^{2+\delta} < \infty, \quad (31)$$

for some $\delta > 0$.

Without loss of any generality let $\delta = 2$ and examine firstly $E_\theta \left| \frac{\partial \ln f(x, \theta)}{\partial \mu} \right|^{2+\delta}$.

Then,

$$E_{\theta} \left| \frac{\partial \ln f(x, \theta)}{\partial \mu} \right|^{2+\delta} = E_{\theta} \left[\left(\frac{x-\mu}{\sigma^2} \right)^4 \right] = \frac{3\sigma^4}{\sigma^8} = \frac{3}{\sigma^4}, \quad (32)$$

that for $\sigma^2 \neq 0$ is $< \infty$. This proves (30).

Let us consider now $E_{\theta} \left| \frac{\partial \ln f(x, \theta)}{\partial \sigma^2} \right|^{2+\delta}$ with $\delta = 2$. Then,

$$E_{\theta} \left| \frac{\partial \ln f(x, \theta)}{\partial \sigma^2} \right|^{2+\delta} = E_{\theta} \left[\left(-\frac{1}{2\sigma^2} + \frac{1}{2\sigma^4} (x-\mu)^2 \right)^4 \right]. \quad (33)$$

Developing the fourth power in (33) we obtain

$$\begin{aligned} & E_{\theta} \left[\left(-\frac{1}{2\sigma^2} \right)^4 + 4 \left(-\frac{1}{2\sigma^2} \right)^3 \left(\frac{1}{2\sigma^4} (x-\mu)^2 \right) + 6 \left(-\frac{1}{2\sigma^2} \right)^2 \left(\frac{1}{2\sigma^4} (x-\mu)^2 \right)^2 \right. \\ & \quad \left. + 4 \left(-\frac{1}{2\sigma^2} \right) \left(\frac{1}{2\sigma^4} (x-\mu)^2 \right)^3 + \left(\frac{1}{2\sigma^4} (x-\mu)^2 \right)^4 \right] = \\ & = E_{\theta} \left[\frac{1}{16\sigma^8} - 4 \frac{1}{8\sigma^6} \frac{1}{2\sigma^4} (x-\mu)^2 + 6 \frac{1}{4\sigma^4} \frac{1}{4\sigma^8} (x-\mu)^4 \right. \\ & \quad \left. - \frac{4}{2\sigma^2} \frac{1}{8\sigma^{12}} (x-\mu)^6 + \frac{1}{16\sigma^{16}} (x-\mu)^8 \right] = \\ & = E_{\theta} \left[\frac{1}{16\sigma^8} - \frac{1}{4\sigma^{10}} (x-\mu)^2 + 3 \frac{1}{8\sigma^{12}} (x-\mu)^4 - \frac{1}{4\sigma^{14}} (x-\mu)^6 + \frac{1}{16\sigma^{16}} (x-\mu)^8 \right]. \end{aligned} \quad (34)$$

Since, for symmetric distributions

$$E_{\theta} \left[(x-\mu)^{2k} \right] = \frac{(2k!)}{2^k k!} (\sigma^2)^k, \quad (35)$$

for any integer k , the (32) becomes

$$E_{\theta} \left| \frac{\partial \ln f(x, \theta)}{\partial \sigma^2} \right|^{2+2} = \left[\frac{1}{16\sigma^8} - \frac{1}{4\sigma^{10}} \sigma^2 + 3 \frac{1}{8\sigma^{12}} \frac{4!}{4 \cdot 2!} \sigma^4 \right. \\ \left. - \frac{1}{4\sigma^{14}} \frac{6!}{8 \cdot 3!} \sigma^6 + \frac{1}{16\sigma^{16}} \frac{8!}{16 \cdot 4!} \sigma^8 \right] = \frac{15}{4\sigma^8}, \quad (36)$$

that for $\sigma^2 \neq 0$ is $< \infty$. This proves (31) and consequently condition C8 holds.

Condition C9 holds

Proof.

Let us consider the function $h(\theta)$ which in our case is defined as

$$\begin{aligned}
h(\boldsymbol{\theta}) &= \ln\left((C_{pmk})^2\right) - \ln(C_{pmk0}^2) = \ln\left[\frac{(d/\sigma - |\xi|)^2}{9(1+\xi^2)C_{pmk0}^2}\right] \\
&= \ln\left[\frac{(d/\sqrt{\sigma^2} - |\xi|)^2}{9(1+\xi^2)C_{pmk0}^2}\right],
\end{aligned} \tag{37}$$

with $\boldsymbol{\theta} = \sigma^2$ scalar.

The (partial) derivative of $h(\boldsymbol{\theta})$ is

$$\frac{\partial h(\boldsymbol{\theta})}{\partial \sigma^2} = \frac{d[\sqrt{\sigma^2}|\xi| - d]}{\sigma^2(\xi^2\sigma^2 - 2d|\xi|\sqrt{\sigma^2} + d^2)} \tag{38}$$

and the subset Θ_0 is $\boldsymbol{\theta}_0 = \sigma_0^2$. Then, we have

$$\lim_{\sigma^2 \rightarrow \sigma_0^2} \frac{\partial h(\boldsymbol{\theta})}{\partial \sigma^2} = \frac{d[\sqrt{\sigma_0^2}|\xi| - d]}{\sigma_0^2(\xi^2\sigma_0^2 - 2d|\xi|\sqrt{\sigma_0^2} + d^2)}. \tag{39}$$

Therefore, the (partial) derivative is a continuous function as requested.

Furthermore,

$$H(\boldsymbol{\theta}) = \frac{d[\sqrt{\sigma^2}|\xi| - d]}{\sigma^2(\xi^2\sigma^2 - 2d|\xi|\sqrt{\sigma^2} + d^2)}$$

is of rank $q=1$. These results satisfy condition C9.

Appendix B: Scenario Details

In the sequential test, or equivalently in the S-SP, for each value of C_{pmk0} and C_{pmk1} , in order to obtain scenarios perfectly comparable with those of the PL-test (or the WP-SP), we set $\xi = 0.5$.

Therefore, the values of the process standard deviations, under H_0 and H_1 , are obtained as

$$\sigma_0 = \frac{d}{3(C_{pmk0})\sqrt{1+\xi^2} + |\xi|}$$

and

$$\sigma_1 = \frac{d}{3(C_{pmk1})\sqrt{1+\xi^2} + |\xi|},$$

respectively.

Without loss of any generality, we considered processes with $d=1$ and $\mu = 0$. Therefore, we generated observations from normal distributions with $\mu = 0$ and standard deviations σ_0 and σ_1 under H_0 and H_1 respectively.

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